New Trends in Computer Vision and Image Processing

Guest Editors:

Prof. Dr. Lihua You
National Centre for Computer Animation, Bournemouth University, Bournemouth BH12 5BB, UK

Dr. Shaojun Bian
School of Creative and Digital Industries, Buckinghamshire New University, High Wycombe HP11 2JZ, UK

Dr. Diqiong Jiang
Centre for Computer Animation, Bournemouth University, Bournemouth BH12 5BB, UK

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Message from the Guest Editors

This Special Issue entitled "New Trends in Computer Vision and Image Processing" invites original research and comprehensive reviews, including but not limited to the following topics:

- Image classification and recognition;
- Object detection and tracking;
- Image segmentation and feature extraction;
- Artificial intelligence techniques of machine learning for computer animation and image processing;
- 3D vision and reconstruction;
- Image enhancement and restoration techniques;
- Image retrieval;
- Biomedical image processing and analysis;
- Applications of computer vision in robotics and automation;
- Ethical considerations and societal impacts of computer vision technologies.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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